

HORI et al. -- Appln. No. 09/867,418
Client/Matter: 061063-0281359

IN THE CLAIMS:

This listing of the claims replaces all prior versions and listings of the claims.

1. (Currently amended) An evaluation method for polycrystalline silicon which is used as a material for pulling single crystal silicon, comprising the steps of:
immersing a predetermined amount of the polycrystalline silicon in a predetermined amount of an agent contained in a vessel, which agent is capable of dissolving the polycrystalline silicon; and
placing a measuring device in the agent having the polycrystalline silicon dissolved therein to count the number of selected foreign particles of a predetermined size dispersed in the agent so as to predict a free ratio of a single crystal silicon which is to be pulled.
2. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, wherein the measuring device is a particle counter
3. (Original) An evaluation method for polycrystalline silicon as set forth in claim 1, wherein the polycrystalline silicon immersed in the agent is aggregated or in pellet shape.
4. (Original) An evaluation method for polycrystalline silicon as set forth in claim 2, wherein the polycrystalline silicon immersed in the agent is aggregated or in pellet shape.
5. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, further comprising the step of:
analyzing the composition of the foreign particles.
6. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 2, further comprising the step of:
analyzing the composition of the foreign particles.
7. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, wherein said foreign particles cause crystal defects.

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8. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 5, wherein the analysis is carried out using scanning electron microscopy or energy dispersive X-ray spectroscopy.
9. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, further comprising the step of:
- subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.
10. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 2, further comprising the step of:
- subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.
11. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 3, further comprising the step of:
- subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.
12. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 4, further comprising the step of:
- subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.
13. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 5, further comprising the step of:
- subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.
14. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 6, further comprising the step of:

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subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.

15. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 7, further comprising the step of:

subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.

16. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 8, further comprising the step of:

subjecting the agent to a circulation filtering process prior to the immersion of the polycrystalline silicon in the agent.

17. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, wherein counting the number of foreign particles includes using a measuring device.

18. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 17, wherein the measuring device is a particle counter.

19. (Previously presented) An evaluation method for polycrystalline silicon as set forth in claim 1, wherein the agent is hydrofluoric acid and nitric acid.

20. (Previously presented) An evaluation method according to claim 1, wherein said agent is an etchant.

21. (New) An evaluation method according to claim 1, wherein the agent having the polycrystalline silicon dissolved therein is a liquid when the measuring device is placed therein.

22. (New) An evaluation method according to claim 1, further comprising the step of:
determining the kind or origin of the selected foreign particles.

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23. (New) An evaluation method according to claim 1, wherein the selected foreign particles are attached to or contained in the polycrystalline silicon.